











SN74LVC1G125-Q1

SGES002D - APRIL 2003-REVISED AUGUST 2019

SN74LVC1G125-Q1 Single-BUS buffer gate with 3-state output

Features

- AEC-Q100 Qualified With the Following Results:
 - Device Temperature Grade 1: –40°C to +125°C Ambient Operating Temperature
 - Device Human-Body Model (HBM) ESD Classification Level 2
 - Device Charged-Device Model (CDM) ESD Classification Level C5
- Available in the small 1.45-mm² package (DRY) With 0.5-mm Pitch
- Supports 5-V V_{CC} Operation
- Over-voltage tolerant inputs accept voltages to 5.5 V
- Provides down translation to V_{CC}
- Max t_{pd} of 3.7 ns at 3.3 V
- Low power consumption, 10-μA Max I_{CC}
- ±24-mA Output drive at 3.3 V
- I_{off} supports live insertion, partial-power-down mode, and back-drive protection
- Latch-up performance exceeds 100 mA Per JESD 78, Class II

2 Applications

- **Qualified for Automotive Applications**
- Increase digital signal drive strength
- Redrive up to 100 MHz square wave signals
- Enable or disable a digital signal with highimpedance off state

3 Description

This bus buffer gate is designed for 1.65-V to 5.5-V V_{CC} operation.

The SN74LVC1G125-Q1 device is a single line driver with a 3-state output. The output is disabled when the output-enable (OE) input is high.

The CMOS device has high output drive while maintaining low static power dissipation over a broad V_{CC} operating range.

The SN74LVC1G125-Q1 device is available in a variety of packages including the small DRY package with a body size of 1.45 mm x 1.00 mm.

Device Information⁽¹⁾

DEVICE NAME	PACKAGE	BODY SIZE (NOM)
1P1G125QDCKRQ1	SOT-23 (5)	2.90 mm × 1.60 mm
CLVC1G125QDBVRQ1	SC70 (5)	2.00 mm x 1.25 mm
1P1G125QDRYRQ1	SON (6)	1.45 mm × 1.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

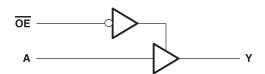




Table of Contents

1	Features 1		8.2 Functional Block Diagram 1	(
2	Applications 1		8.3 Feature Description 1	
3	Description 1		8.4 Device Functional Modes 1	1
4	Revision History2	9	Application and Implementation 1	
5	Pin Configuration and Functions 3		9.1 Application Information 1	
6	Specifications4		9.2 Typical Application	ď
•	6.1 Absolute Maximum Ratings	10	Power Supply Recommendations 1	2
	6.2 ESD Ratings	11	Layout1	2
	6.3 Recommended Operating Conditions 5		11.1 Layout Guidelines 1	1
	6.4 Thermal Information		11.2 Layout Example 1	1
	6.5 Electrical Characteristics	12	Device and Documentation Support 1	;
	6.6 Switching Characteristics 6		12.1 Receiving Notification of Documentation Updates 1	1
	6.7 Operating Characteristics 6		12.2 Community Resources 1	į
	6.8 Typical Characteristics		12.3 Trademarks 1	1
7	Parameter Measurement Information 8		12.4 Electrostatic Discharge Caution 1	ľ
8	Detailed Description		12.5 Glossary 1	1
·	8.1 Overview	13	Mechanical, Packaging, and Orderable Information 1	;

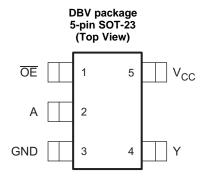
4 Revision History

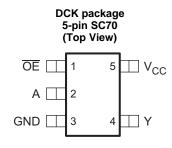
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

CI	hanges from Revision C (April 2008) to Revision D	Page
•	Changed data sheet format to new TI standard	
•	Added DRY package to Pin Configuration and Functions	3
•	Added Pin Functions table.	3
•	Added Handling Ratings table.	4
•	Added Thermal Information table.	5
•	Added –40°C to 125°C Temperature range to Electrical Characteristics	6
•	Added Detailed Description section.	10
•	Added Application and Implementation section.	11
•	Added Layout section.	12

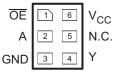


5 Pin Configuration and Functions





DRY package 6-pin SON (Transparent Top View)



N.C. – No internal connection
See mechanical drawings for dimensions.

Pin Functions

PIN		I/O	DESCRIPTION	
NAME	DBV, DCK	DRY	1/0	DESCRIPTION
ŌĒ	1	1	Input	Active low Output Enable Input
Α	2	2	Input	Input A
GND	3	3	_	Ground
Υ	4	4	Output	Output Y
V _{CC}	5	6	_	Positive supply
NC	-	5	_	No internal connection

Product Folder Links: SN74LVC1G125-Q1



6 Specifications

6.1 Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range	Supply voltage range		6.5	V
VI	Input voltage range ⁽²⁾		-0.5	6.5	V
Vo	Voltage range applied to any output in the high-i	Voltage range applied to any output in the high-impedance or power-off state (2)		6.5	V
Vo	Voltage range applied to any output in the high or low state (2)(3)		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		-50	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
Io	Continuous output current			±50	mA
	Continuous current through V _{CC} or GND			±100	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
V Flastus static disabases	Flootrootatio discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾ HBM ESD Classification Level	±2000	V
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011 CDM ESD Classification Level	±1000	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

⁽²⁾ The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ The value of V_{CC} is provided in the *Recommended Operating* table.



6.3 Recommended Operating Conditions⁽¹⁾

			MIN	MAX	UNIT	
,	Owner have the me	Operating	1.65	5.5		
/ _{cc}	Supply voltage	Data retention only	1.5		V	
		V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}			
,	I Park Toward Samuel Control	V _{CC} = 2.3 V to 2.7 V	1.7		V	
V _{IH}	High-level input voltage	V _{CC} = 3 V to 3.6 V	2		V	
		V _{CC} = 4.5 V to 5.5 V	0.7 × V _{CC}			
		V _{CC} = 1.65 V to 1.95 V		0.35 × V _{CC}		
.,	Low lovel input voltage	V _{CC} = 2.3 V to 2.7 V		0.7	.,	
V_{IL}	Low-level input voltage	V _{CC} = 3 V to 3.6 V		0.8	V	
	V _{CC} = 4.5 V to 5.5 V		0.3 × V _{CC}			
VI	Input voltage	•	0	5.5	V	
V _O	Output voltage		0	V _{CC}	V	
	V _{CC} = 1.65 V		-4			
		V _{CC} = 2.3 V		-8		
ОН	High-level output current	V 2V		-16	mA	
		$V_{CC} = 3 V$		-24		
		V _{CC} = 4.5 V		-24		
		V _{CC} = 1.65 V		4		
		V _{CC} = 2.3 V		8		
OL	Low-level output current	V 2 V		16	mA	
		V _{CC} = 3 V		24		
		V _{CC} = 4.5 V		24		
		V _{CC} = 1.8 V ± 0.15 V, 2.5 V ± 0.2 V		20		
∆t/∆v	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		10		
		V _{CC} = 5 V ± 0.5 V		5		
T _A	Operating free-air temperature		-40	125	°C	

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

6.4 Thermal Information

			SN74LVC1G125-Q1			
	THERMAL METRIC(1)	DBV	DCK	DRY	UNIT	
		5 PINS	5 PINS	6 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	229	278	439	°C/W	
R ₀ JC(top)	Junction-to-case (top) thermal resistance	164	93	277	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	62	65	271	°C/W	
ΤιΨ	Junction-to-top characterization parameter	44	2	84	°C/W	
ΨЈВ	Junction-to-board characterization parameter	62	64	271	°C/W	
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	-	_	_	°C/W	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

Product Folder Links: SN74LVC1G125-Q1



6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST SOURITIONS	.,	−40 °C	to 125 °C			
PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP ⁽¹⁾	MAX	UNIT	
	I _{OH} = -100 μA	1.65 V to 5.5 V	V _{CC} - 0.1				
	$I_{OH} = -4 \text{ mA}$	1.65 V	1.2				
.,	$I_{OH} = -8 \text{ mA}$	2.3 V	1.9			V	
V _{OH}	I _{OH} = -16 mA	3 V	2.4			V	
	1 24 mA	3 V	2.3				
	$I_{OH} = -24 \text{ mA}$	4.5 V	3.8				
	I _{OL} = 100 μA	1.65 V to 5.5 V			0.1		
	I _{OL} = 4 mA	1.65 V			0.45		
M	I _{OL} = 8 mA	2.3 V			0.3	V	
V _{OL}	I _{OL} = 16 mA	3 V			0.4		
	1 24 mA	3 V			0.55		
	I _{OL} = 24 mA	4.5 V			0.55		
I _I A or \overline{OE} inputs	V _I = 5.5 V or GND	0 to 5.5 V			±5	μА	
I _{off}	V_I or $V_O = 5.5 \text{ V}$	0			±10	μΑ	
I_{OZ} $V_O = 0 \text{ to } 5.5 \text{ V}$		3.6 V			10	μΑ	
Icc	$V_I = 5.5 \text{ V or GND}, \qquad I_O = 0$	1.65 V to 5.5 V			10	μΑ	
Δl _{CC}	One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 5.5 V			500	μА	
C _I	$V_I = V_{CC}$ or GND	3.3 V		4		pF	

⁽¹⁾ All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

6.6 Switching Characteristics

over recommended operating free-air temperature range of -40° C to 125° C, $C_L = 50$ pF (unless otherwise noted) (see Figure 3)

PARAMETER	FROM	TO (OUTPUT)	V _{CC} = 3. ± 0.3	3 V V	V _{CC} = 5 ± 0.5	5 V V	UNIT
	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	
t _{pd}	Α	Υ	1	5.1	1	4.1	ns
t _{en}	ŌĒ	Υ	1	6	1	5	ns
t _{dis}	ŌĒ	Υ	1	5	1	4.2	ns

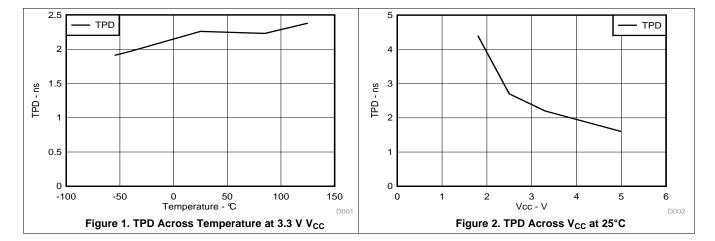
6.7 Operating Characteristics

 $T_A = 25^{\circ}C$

	PARAMETER		TEST CONDITIONS	V _{CC} = 3.3 V TYP	V _{CC} = 5 V TYP	UNIT
0	Power dissipation	Outputs enabled	f 40 MH=	19	21	, F
C _{pd}	capacitance	Outputs disabled	f = 10 MHz	2	4	p⊦

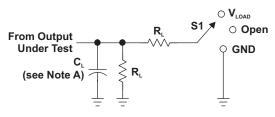


6.8 Typical Characteristics





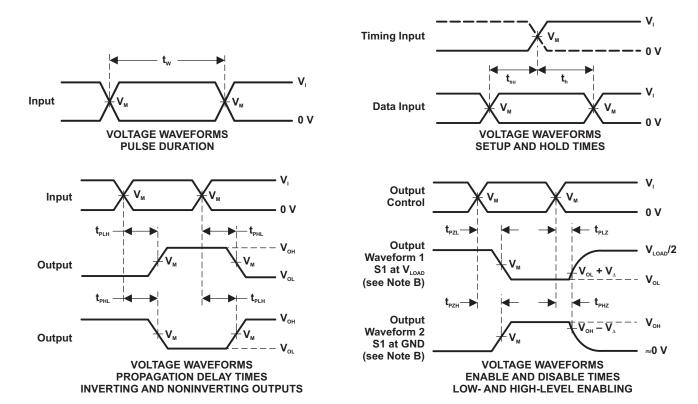
7 Parameter Measurement Information



TEST	S1
t _{PLH} /t _{PHL}	Open
$t_{_{PLZ}}/t_{_{PZL}}$	V _{LOAD}
t _{PHZ} /t _{PZH}	GND

LOAD CIRCUIT

.,	INI	PUTS	.,,	v		-	.,	
V _{cc}	V,	t,/t,	V _M	V _{LOAD}	C _∟	$R_{\scriptscriptstyle L}$	V _A	
1.8 V ± 0.15 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	15 pF	1 M Ω	0.15 V	
2.5 V ± 0.2 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	15 pF	1 M Ω	0.15 V	
3.3 V ± 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	15 pF	1 M Ω	0.3 V	
5 V ± 0.5 V	V _{cc}	≤2.5 ns	V _{cc} /2	2 × V _{cc}	15 pF	1 Μ Ω	0.3 V	



NOTES: A. C, includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{\circ} = 50 Ω .
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and \dot{t}_{PHZ} are the same as t_{dis} .
- F. $t_{\mbox{\tiny PZL}}$ and $t_{\mbox{\tiny PZH}}$ are the same as $t_{\mbox{\tiny en}}.$
- G. t_{PlH} and t_{PHl} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

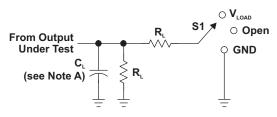
Figure 3. Load Circuit and Voltage Waveforms

Submit Documentation Feedback

Copyright © 2003–2019, Texas Instruments Incorporated



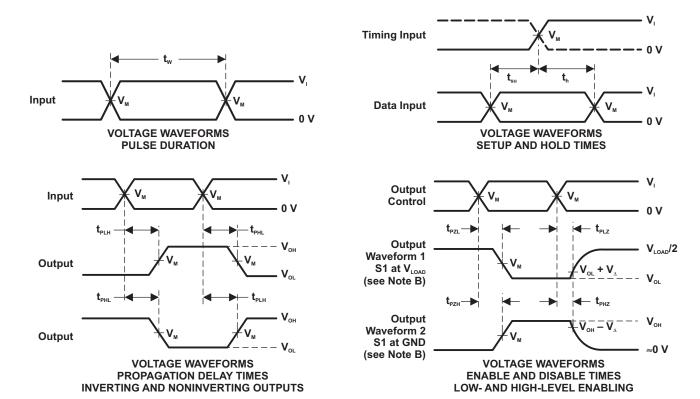
Parameter Measurement Information (continued)



TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	V _{LOAD}
t _{PHZ} /t _{PZH}	GND

LOAD CIRCUIT

.,	INI	PUTS		V		-	.,
V _{cc}	V,	t,/t,	V _M	V _{LOAD}	C _∟	R _⊾	V _A
1.8 V ± 0.15 V	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	30 pF	1 k Ω	0.15 V
$2.5~V~\pm~0.2~V$	V _{cc}	≤2 ns	V _{cc} /2	2 × V _{cc}	30 pF	500 Ω	0.15 V
$3.3 \text{ V} \pm 0.3 \text{ V}$	3 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V
5 V ± 0.5 V	V _{cc}	≤2.5 ns	V _{cc} /2	2 × V _{cc}	50 pF	500 Ω	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \,\Omega$.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and \dot{t}_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. $t_{\text{PLH}}^{\text{F2L}}$ and $t_{\text{PHL}}^{\text{F2L}}$ are the same as $t_{\text{pd}}^{\text{eff}}$
- H. All parameters and waveforms are not applicable to all devices.

Figure 4. Load Circuit and Voltage Waveforms



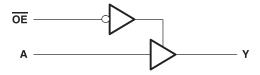
8 Detailed Description

8.1 Overview

The SN74LVC1G125-Q1 device contains one buffer gate device with output enable control and performs the Boolean function Y = A. This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

To ensure the high-impedance state during power up or power down, $\overline{\text{OE}}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

8.2 Functional Block Diagram



8.3 Feature Description

- Wide operating voltage range
 - Operates from 1.65 V to 5.5 V
- · Allows down voltage translation
- Inputs accept voltages to 5.5 V
- I_{off} feature allows voltages on the inputs and outputs, when V_{CC} is 0 V

8.4 Device Functional Modes

Table 1. Function Table

INP	UTS	OUTPUT
ŌĒ	Α	Υ
L	Н	Н
L	L	L
Н	X	Z



Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The SN74LVC1G125-Q1 device is a high drive CMOS device that can be used as a output enabled buffer with a high output drive, such as an LED application. It can produce 24 mA of drive current at 3.3 V making it Ideal for driving multiple outputs and good for high speed applications up to 100 MHz. The inputs are 5.5 V tolerant allowing it to translate down to V_{CC}.

9.2 Typical Application

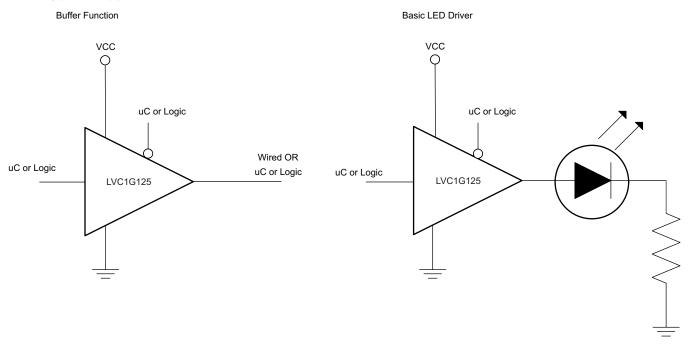


Figure 5. Typical Application Schematic

9.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Care should be taken to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads so routing and load conditions should be considered to prevent ringing.

9.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions
 - Rise time and fall time specs. See (Δt/ΔV) in the Recommended Operating Conditions table.
 - Specified high and low levels. See (V_{IH} and V_{II}) in the Recommended Operating Conditions table.
 - Inputs are overvoltage tolerant allowing them to go as high as (V_I max) in the Recommended Operating Conditions table at any valid V_{CC}.

2. Recommend Output Conditions

Copyright © 2003-2019, Texas Instruments Incorporated

 Load currents should not exceed (I_O max) per output and should not exceed (Continuous current through V_{CC} or GND) total current for the part. These limits are located in the *Absolute Maximum Ratings* table.



Typical Application (continued)

Outputs should not be pulled above V_{CC}.

9.2.3 Application Curves

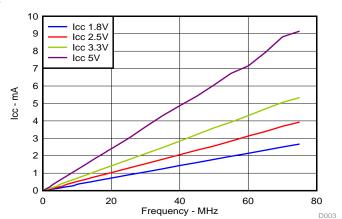


Figure 6. I_{CC} vs Frequency, Square wave input signal

10 Power Supply Recommendations

The power supply can be any voltage between the min and max supply voltage rating located in the *Recommended Operating Conditions* table.

Each V_{CC} pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply a 0.1- μ F capacitor is recommended and if there are multiple VCC pins then a 0.01- μ F or 0.022- μ F capacitor is recommended for each power pin. It is ok to parallel multiple bypass caps to reject different frequencies of noise. 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

11 Layout

11.1 Layout Guidelines

When using multiple bit logic devices inputs should not ever float. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Figure 7 shows the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or VCC, whichever makes more sense or is more convenient.

11.2 Layout Example



Figure 7. Package Layout



12 Device and Documentation Support

12.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.3 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: SN74LVC1G125-Q1

Copyright © 2003-2019, Texas Instruments Incorporated





6-Feb-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
1P1G125QDCKRG4Q1	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CMR	Samples
1P1G125QDCKRQ1	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CMR	Samples
1P1G125QDRYRQ1	ACTIVE	SON	DRY	6	5000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 125	FX	Samples
CLVC1G125QDBVRQ1	ACTIVE	SOT-23	DBV	5	3000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 125	C25O	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and



PACKAGE OPTION ADDENDUM

6-Feb-2020

continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74LVC1G125-Q1:

● Enhanced Product: SN74LVC1G125-EP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 7-Sep-2019

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
1P1G125QDCKRQ1	SC70	DCK	5	3000	180.0	8.4	2.47	2.3	1.25	4.0	8.0	Q3
1P1G125QDRYRQ1	SON	DRY	6	5000	180.0	9.5	1.2	1.65	0.7	4.0	8.0	Q1
CLVC1G125QDBVRQ1	SOT-23	DBV	5	3000	179.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3

www.ti.com 7-Sep-2019



*All dimensions are nominal

Device	Package Type Package Drawing		Device Package Type Package Drawing P		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
1P1G125QDCKRQ1	SC70	DCK	5	3000	202.0	201.0	28.0		
1P1G125QDRYRQ1	SON	DRY	6	5000	189.0	185.0	36.0		
CLVC1G125QDBVRQ1	SOT-23	DBV	5	3000	203.0	203.0	35.0		



SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Reference JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)



^{7.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

^{8.} Board assembly site may have different recommendations for stencil design.

DCK (R-PDSO-G5)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
- D. Falls within JEDEC MO-203 variation AA.



DCK (R-PDSO-G5)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.





Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

Tl's products are provided subject to Tl's Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such Tl products. Tl's provision of these resources does not expand or otherwise alter Tl's applicable warranties or warranty disclaimers for Tl products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2020, Texas Instruments Incorporated